



# Electron-Solid Interactions

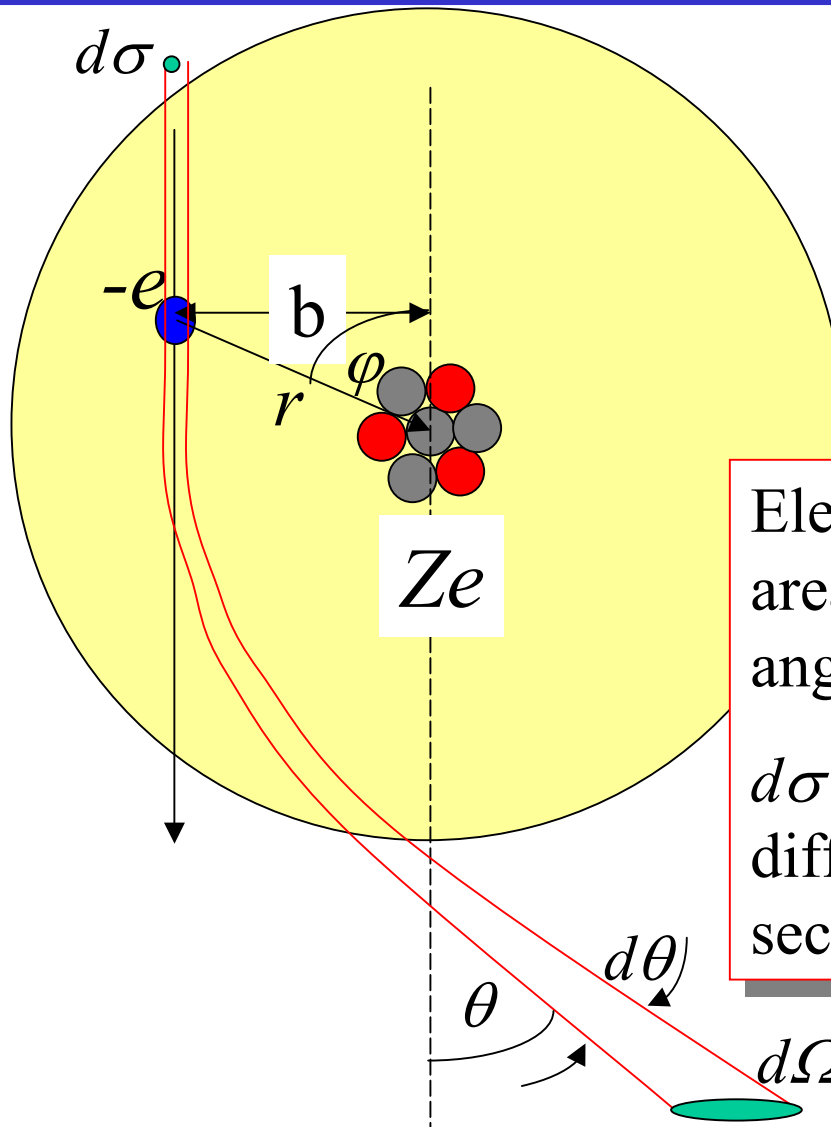


- Where do they go?
  - Elastic scattering
    - Single scattering
    - Plural scattering
    - Continuous slowing down approximation
    - Multiple scattering/diffusion
- What do they do?
  - Inelastic scattering
    - Energy loss mechanisms



Ludwig Reimer, *"Scanning Electron Microscopy"*, Springer-Verlag (1985)

Ludwig Reimer, *"Transmission Electron Microscopy"*, 4<sup>th</sup>, Springer-Verlag (1997)



$$F = -\frac{e^2 Z}{4\pi\epsilon_0 r^2} \mathbf{u}_r$$

Electrons that pass through the area  $d\sigma$  are scattered through the angle  $\theta$  into a solid angle  $d\Omega$ .

$d\sigma / d\Omega$  is referred to as the differential scattering cross section.



# Rutherford Differential Scattering Cross-Section



Consider angular momentum, resolve motion into horizontal and vertical components. At the start of the trajectory  $v_h$  is zero, at the end  $v_h = v \sin \theta$ .

$$\frac{d\sigma}{d\Omega} = \frac{e^4 Z^2}{4(4\pi\epsilon_0)^2 m^2 v^4} \frac{1}{\sin^4(\theta/2)}$$

- Scattering proportional to  $Z^2$
- Scattering forward peaked
  - Singularity at  $\theta = 0$

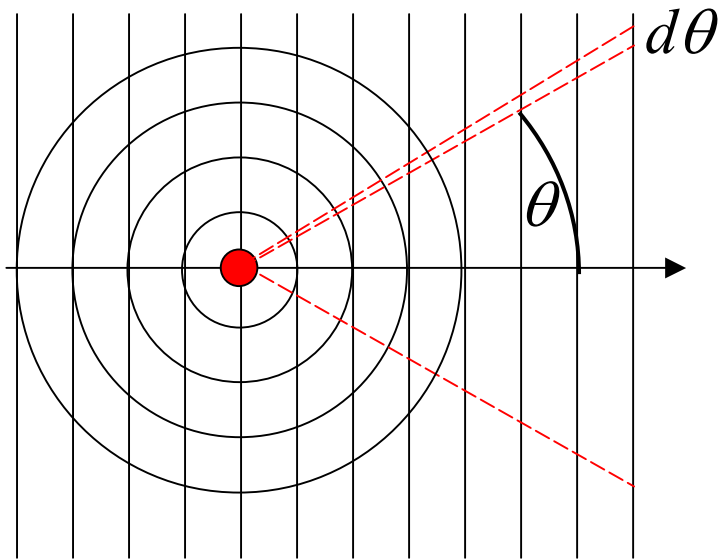




# Elastic Scattering – Other Cross-Sections



- Need to account for screening of nuclear charge by atomic electrons
  - Quantum mechanical treatment considers superposition of plane wave and spherical scattered wave



*Plane wave:*  $\psi = \psi_0 e^{2\pi i k_0 z}$

*Scattered wave:*  $\psi = \psi_0 f(\theta) \frac{e^{2\pi i k_0 r}}{r}$

$$\frac{d\sigma}{d\Omega} = |f(\theta)|^2$$

- $f(\theta)$  is the angle dependent scattering amplitude and represents Fraunhofer (far-field) diffraction by the atomic potential
- Numerous cross-sections derived according to form of potential



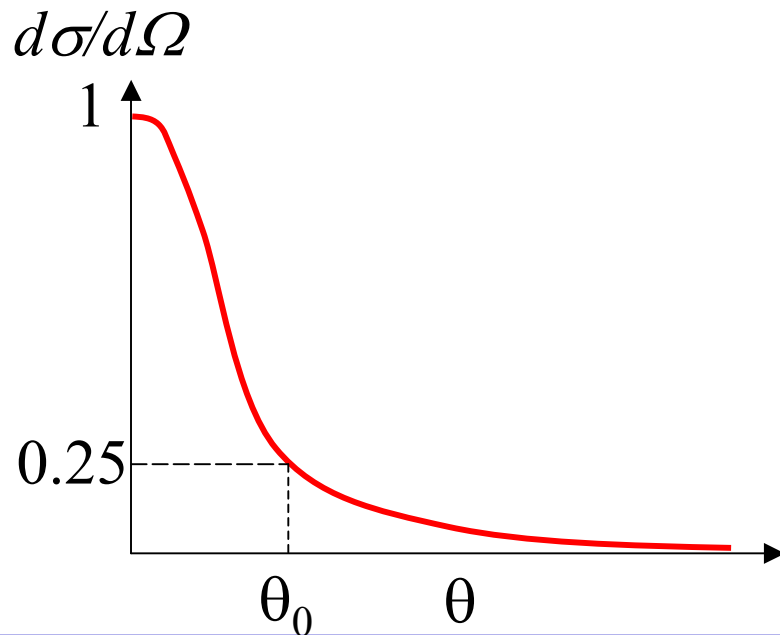


# Screened-Rutherford Cross-Section



$$\frac{d\sigma}{d\Omega} = \frac{4Z^2(1 + E/E_0)}{a_H^2} \frac{1}{\left[1 + (\theta/\theta_0)^2\right]^2}, \theta_0 = \frac{\lambda Z^{1/3}}{2\pi a_H}$$

$\theta_0$  = characteristic scattering angle, typically 10's mrad at 100 kV



Total Elastic Cross-Section

$$\sigma_{elastic} = \frac{Z^{4/3} \lambda^2 (1 + E/E_0)^2}{\pi}$$

Cross-section *increases* as E *decreases*  
Characteristic angle *increases* as E *decreases*





# Mean-Free-Path



$N = \text{atoms/unit volume}$

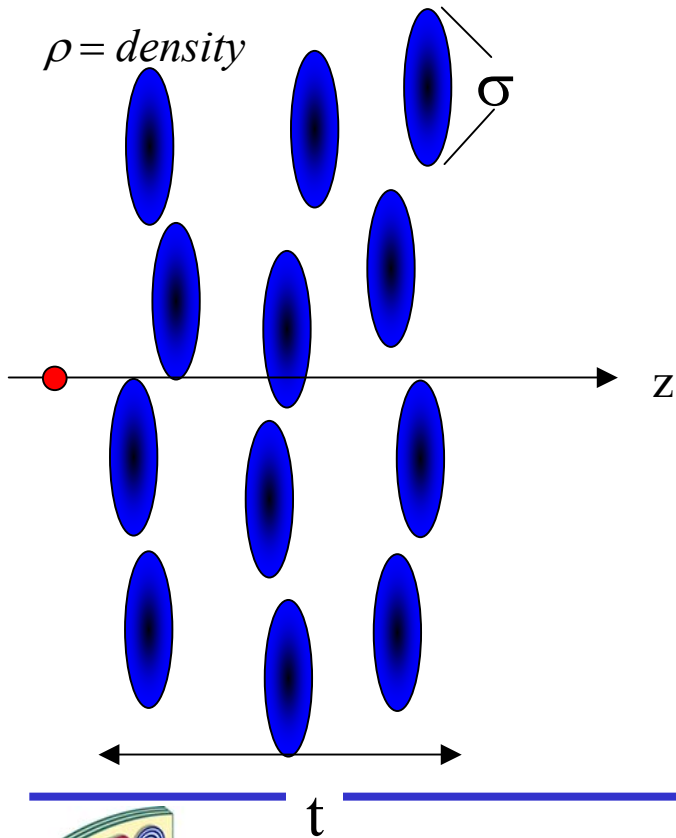
$n = \text{atoms/unit area}$

$n\sigma = \text{scattering area fraction}$

$N_A = \text{Avogadro's number}$

$A = \text{Atomic number}$

$\rho = \text{density}$



$$n = \frac{N_A \rho}{A} t = Nt$$

$$dI = -IN\sigma dz$$

$$I = I_0 e^{-N\sigma t} = I_0 e^{-t/\Lambda}$$

$$\Lambda = \frac{1}{N\sigma} = \text{Mean Free Path}$$

$$P(m) = \frac{(t/\Lambda)^m}{m!} e^{-t/\Lambda}$$

$$P(0) = e^{-t/\Lambda} = \text{fraction unscattered}$$

| Element | Z  | $\Lambda_{50 \text{ kV}}$ (nm) | Range ( $\mu\text{m}$ ) |
|---------|----|--------------------------------|-------------------------|
| C       | 6  | 83                             | 22.6                    |
| Al      | 13 | 49                             | 16.7                    |
| Cu      | 29 | 10.7                           | 5.1                     |
| Ag      | 47 | 7.7                            | 4.3                     |
| Au      | 79 | 4.6                            | 2.3                     |





# Angular Distribution & Beam Broadening



$$I_1(\theta)d\Omega = I_0 n \frac{d\sigma}{d\Omega} d\Omega = I_0 N \sigma t \left( \frac{1}{\sigma} \frac{d\sigma}{d\Omega} \right) d\Omega = I_0 \frac{t}{\Lambda} S_1(\theta) d\Omega, d\Omega = 2\pi \sin \theta$$

$$\int S_1(\theta) 2\pi \sin \theta d\theta = 1 \quad \leftarrow \text{Normalized single scattering function}$$

$$S_m = S_{m-1}(\theta) \otimes S_1(\theta)$$

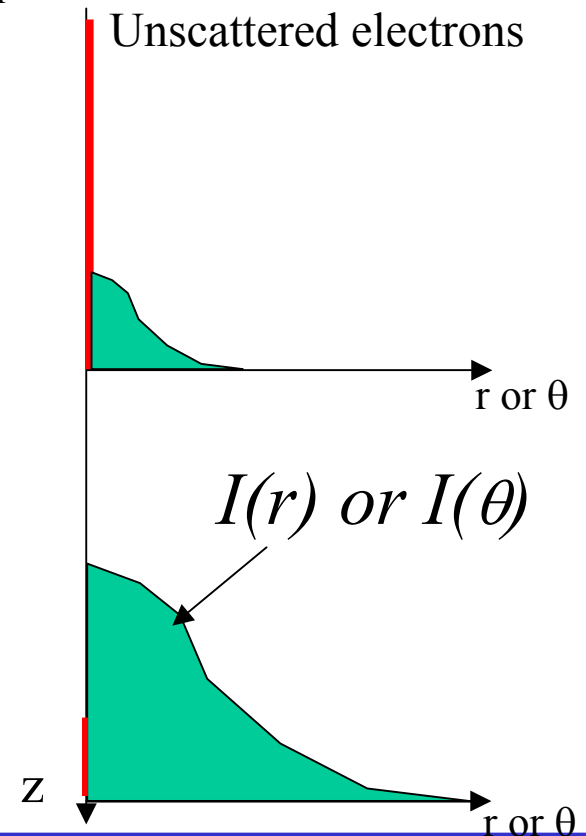
$$I(\theta)d\Omega = I_0 d\Omega \sum_{m=0}^{\infty} \frac{(t/\Lambda)^m}{m!} e^{-t/\Lambda} S_m(\theta)$$

$$\overline{\theta^2} = \frac{t}{\Lambda} \overline{\theta_1^2}, \quad r = \theta z$$

Approximate  $S_1(\theta) \approx e^{-\theta^2 / \overline{\theta_1^2}}$ , assume  $I(r) \propto e^{-r^2 / \overline{r^2}}$

$$\overline{r^2} = \frac{2}{3} \frac{\overline{\theta_1^2}}{\Lambda} t^3, \quad r_{rms} \propto t^{3/2}$$

Appropriate for  $m < 25$

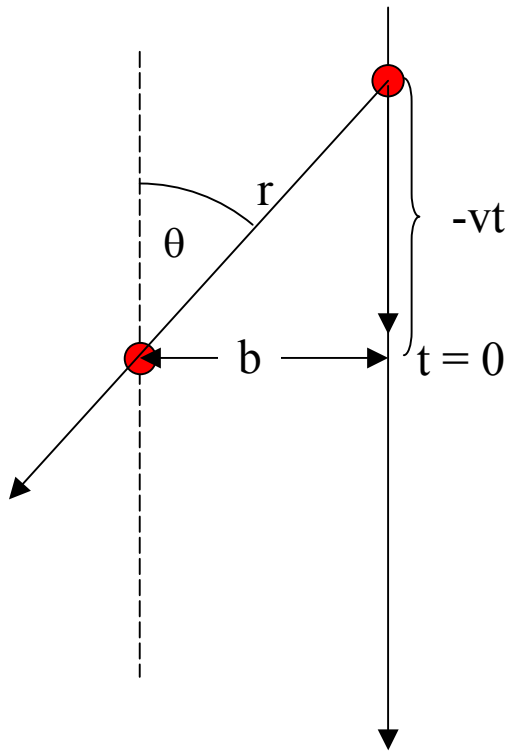




# Continuous Slowing Down Approximation



- Energy transfer,  $W$  ( $\ll E$ , incident electron energy), occurs through Coulomb interaction between incident electrons and atomic electrons. Mean energy loss/path length is  $-dE_m$ . Stopping power,  $S$ :



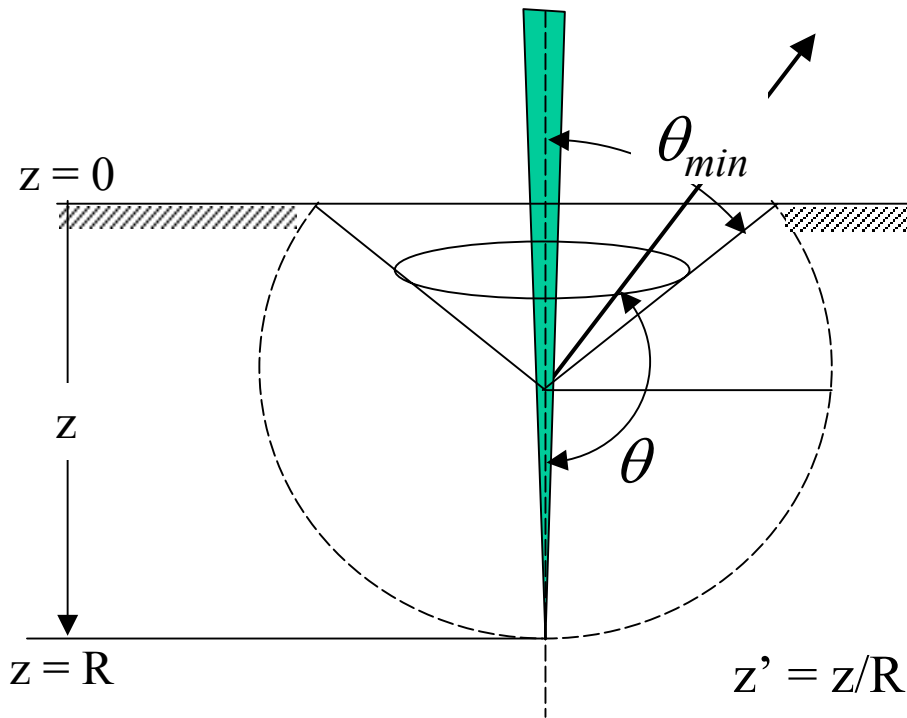
$$S = \left| \frac{dE_m}{ds} \right| = NZ \int_{W_{\min}}^{W_{\max}} \frac{d\sigma}{dW} W dW = \frac{2\pi e^4 N_A \rho Z}{(4\pi\epsilon_0)^2 AE} \int_{b_{\min}}^{b_{\max}} \frac{db}{b}$$

$$= \frac{2\pi e^4 N_A \rho Z}{(4\pi\epsilon_0)^2 AE} \ln\left(\frac{E}{J}\right), \quad J = 11.5Z, \quad Z \leq 6$$

$$\text{Range, } R \propto E^n, \frac{1}{Z^m}, \quad 1.3 \leq n \leq 1.7, m \approx 1$$







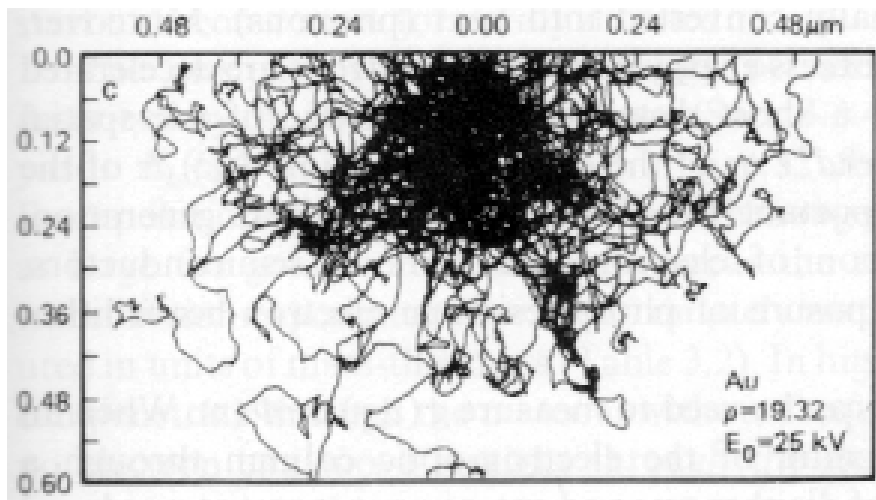
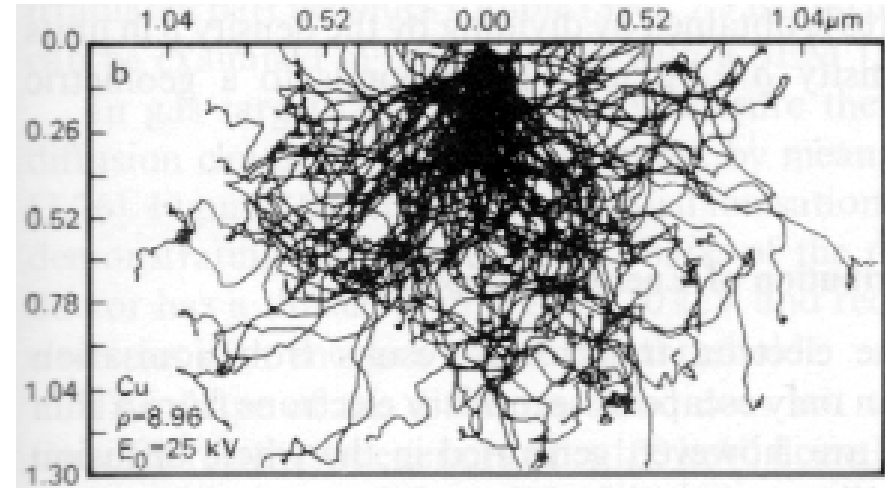
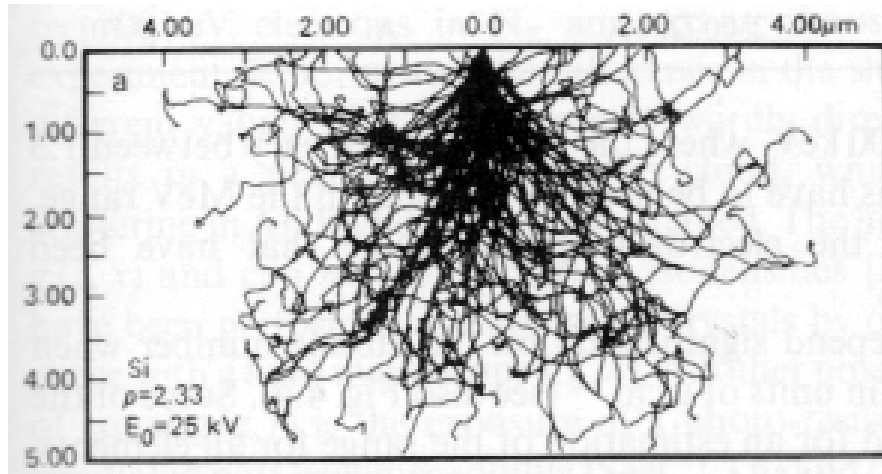
- Electron energy decreases with depth as  $v = (c_T \rho z - v_0^4)^{1/4}$
- Intensity decreases as  $dI(z) = N_A \rho \sigma \pi / (2A) I(z) dz$
- Electrons are backscattered by single scattering through angles  $\pi - \theta_{min} < \theta < \pi$

$$\eta = \int_0^{0.5} \frac{N_A \rho}{A I_0} \sigma(\theta_{min}) I(z') dz' \approx \frac{0.012Z - 1 + 0.5^{0.012Z}}{0.012Z + 1}$$

$\eta$  increases with increasing  $Z$ ,  $R$  decreases with increasing  $Z$ . Character of proximity effect changes with atomic number



# Monte-Carlo Simulation

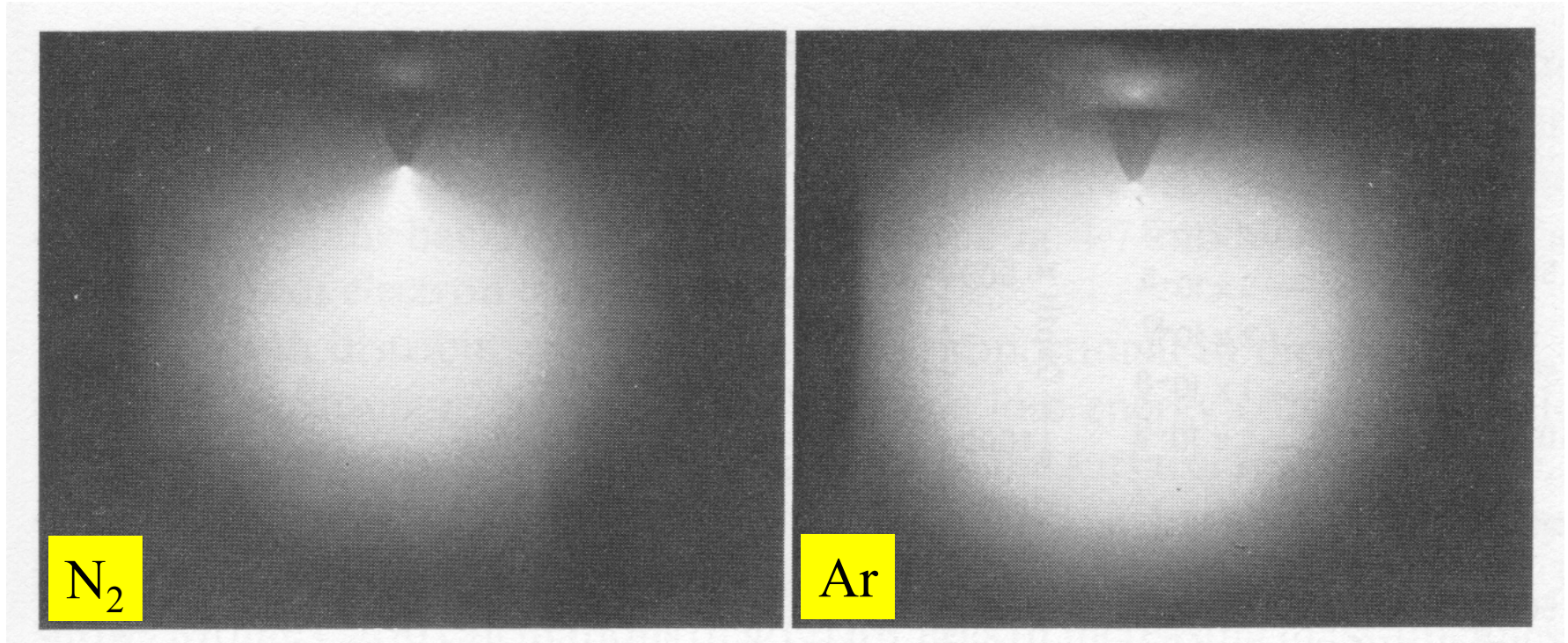


Note changes in horizontal and vertical scales as the atomic number increases: Si 14, Cu 29, Au 79





# Scattering in Gas Targets



Ludwig Reimer, "*Scanning Electron Microscopy*", Springer-Verlag (1985)





# Inelastic Scattering



- Energy loss occurs through a variety of mechanisms
  - Molecular oscillations/phonons
    - $\Delta E = 20 \text{ meV} - 1 \text{ eV}$
  - Conduction/valence electrons
    - Plasmons
    - Inter- or Intra-band transitions
    - $\Delta E = 1 \text{ eV} - 50 \text{ eV}$
  - Core electrons
    - Ionization of inner shell electrons
      - X-rays
      - Auger electrons
    - $\Delta E_K = 110 \text{ eV (Be)} - 80 \text{ keV (Au)}$

Described by dielectric theory - related to optical constants of material. Electron energy-loss spectra and those for light and x-rays are related

Energy loss in C is  $\approx 0.24 \text{ eV/nm}$  at 100 keV





# Plasmon & Optical Losses I



$$m^* \frac{d^2 \mathbf{x}}{dt^2} + m^* \gamma \frac{d\mathbf{x}}{dt} = -e\mathbf{E}$$

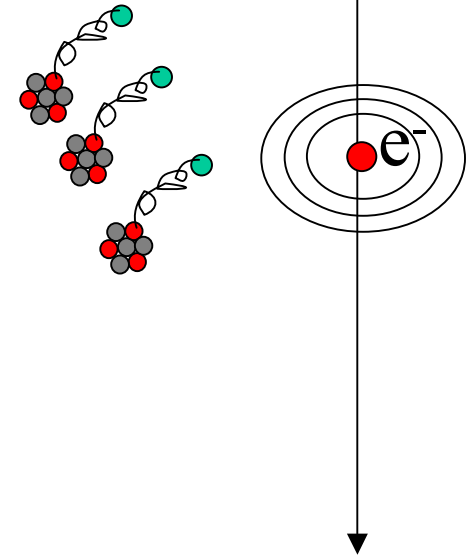
$$\mathbf{x} = \frac{e}{m^* \omega^2} \frac{\omega^2 - i\omega\gamma}{\omega^2 + \gamma^2} \mathbf{E}$$

$$\mathbf{P} = -eN_e \mathbf{x} = \varepsilon_0 \chi_e \mathbf{E}, \quad \varepsilon = \varepsilon_0 (1 + \chi_e)$$

$$\varepsilon(\omega) = \varepsilon_1 + i\varepsilon_2 = \varepsilon_0 \left( 1 - \frac{N_e e^2}{m^* \varepsilon_0} \frac{1}{\omega^2 + i\omega\gamma} \right)$$

$$\Rightarrow \varepsilon_1 = \varepsilon_0 \left( 1 - \frac{\omega_{pl}^2}{\omega^2} \frac{1}{1 + (\gamma/\omega)^2} \right), \quad \varepsilon_2 = \varepsilon_0 \frac{\gamma}{\omega} \frac{\omega_{pl}^2}{\omega^2} \frac{1}{1 + (\gamma/\omega)^2}$$

$$\text{Plasma frequency: } \omega_{pl} = \sqrt{\frac{N_e e^2}{\varepsilon_0 m^*}} \text{ i.e. } \gamma = 0, \quad \text{Plasmon energy: } \Delta E_{pl} = \hbar \omega_{pl}$$





# Plasmon & Optical Losses II



$$m^* \left( \frac{d^2 \mathbf{x}}{dt^2} + \gamma \frac{d\mathbf{x}}{dt} + \omega_b^2 \mathbf{x} \right) = -e\mathbf{E}$$

$$\epsilon(\omega) = \epsilon_0 \left( 1 + \frac{N_e e^2}{\epsilon_0 m^*} \frac{1}{\omega_b^2 - \omega^2 - i\omega\gamma} \right)$$

Introduce oscillators with other characteristic frequencies,  $\omega_b$ , to represent bound electrons. Resonances occur when  $\omega = \omega_b$ . Passage of high-energy electron results in frequency pulse that can excite many resonances.







# Dielectric Theory



Optical constant :  $\varepsilon = \varepsilon_1 + i\varepsilon_2 = (n + ik)^2$

Energy dissipation :  $\frac{dW}{dt} = \dot{\mathbf{E}} \cdot \mathbf{D}$

Electron :  $\rho = e\delta(x - vt)$

$\text{div} \mathbf{D} = \rho$ ,  $\mathbf{E} = \mathbf{E}_0 e^{-i\omega t}$ ,  $\mathbf{D} = \varepsilon \varepsilon_0 \mathbf{E}$

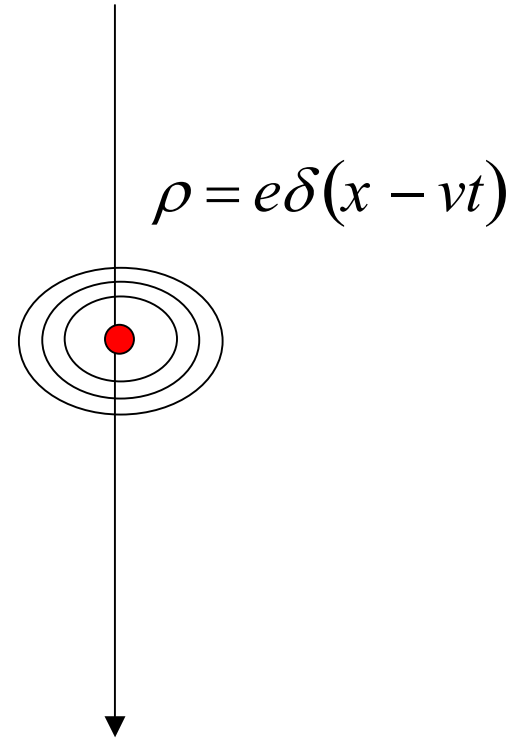
$$\Rightarrow \overline{\frac{dW}{dt}} = \varepsilon_0 \varepsilon_2 \frac{\omega |\mathbf{E}_0|^2}{2} = \frac{1}{\varepsilon_0} \frac{\varepsilon_2}{|\varepsilon|^2} \frac{\omega D_0^2}{2} = \frac{1}{\varepsilon_0} \frac{\omega D_0^2}{2} \text{Im}(-1/\varepsilon)$$

Note :  $\varepsilon \rightarrow f(\omega)$

$$\frac{d^2 \sigma}{d\Delta E d\Omega} = \frac{1}{\pi^2 a_H m v^2 N_e} \frac{\text{Im}(-1/\varepsilon)}{(\theta^2 + \theta_E^2)}, \quad N_e = \text{electrons/unit volume}, \quad \theta_E = \frac{\Delta E}{2E}$$

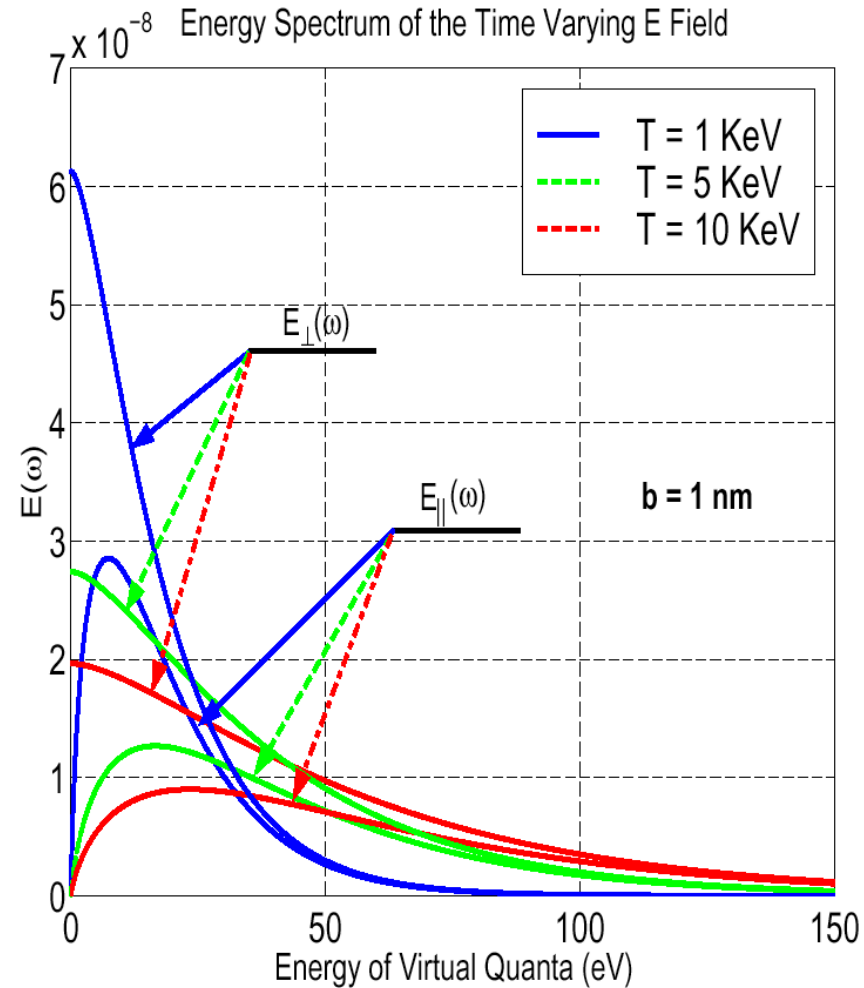
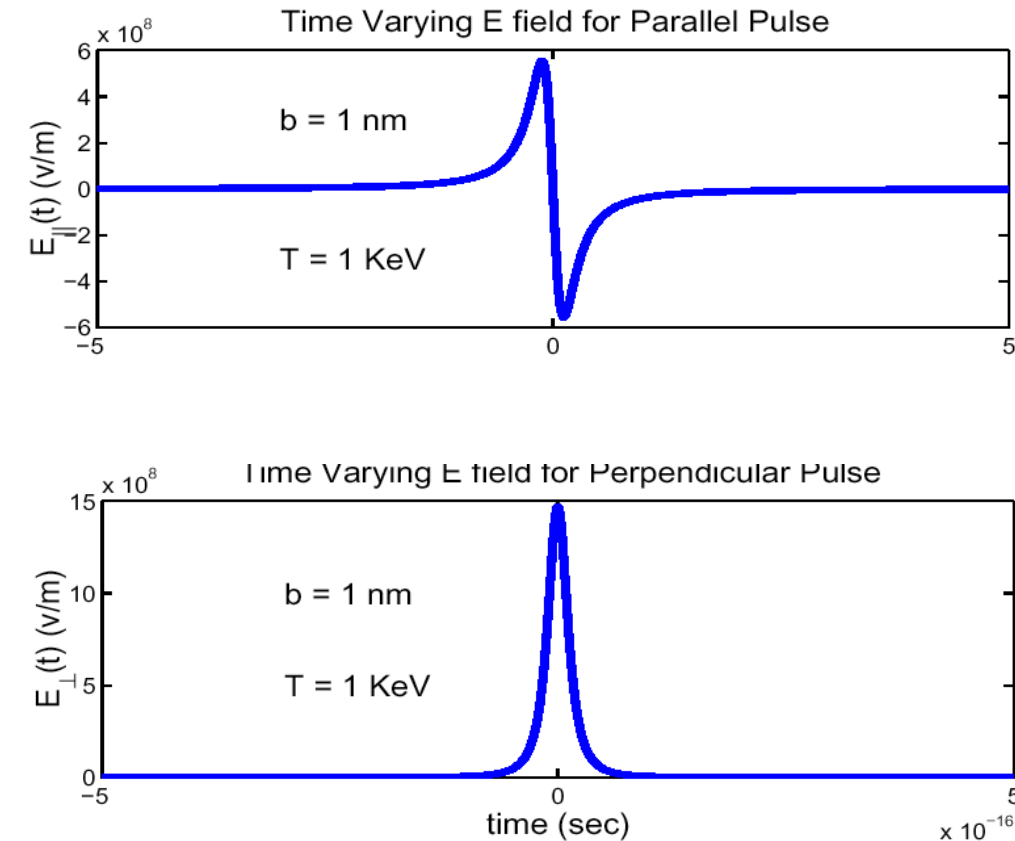
$$\sigma_{\text{inel}} \approx 20 \sigma_{\text{el}}/Z$$

20 eV loss at 100 keV  
gives a  $\theta_E$  of 0.1 mrad





# Method of Virtual Quanta

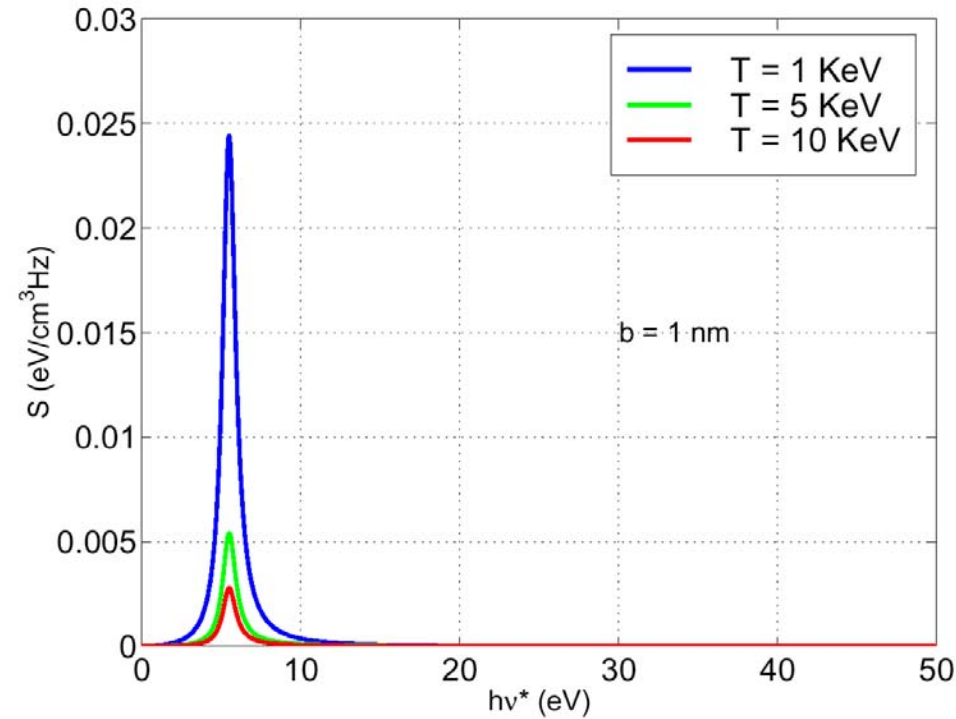
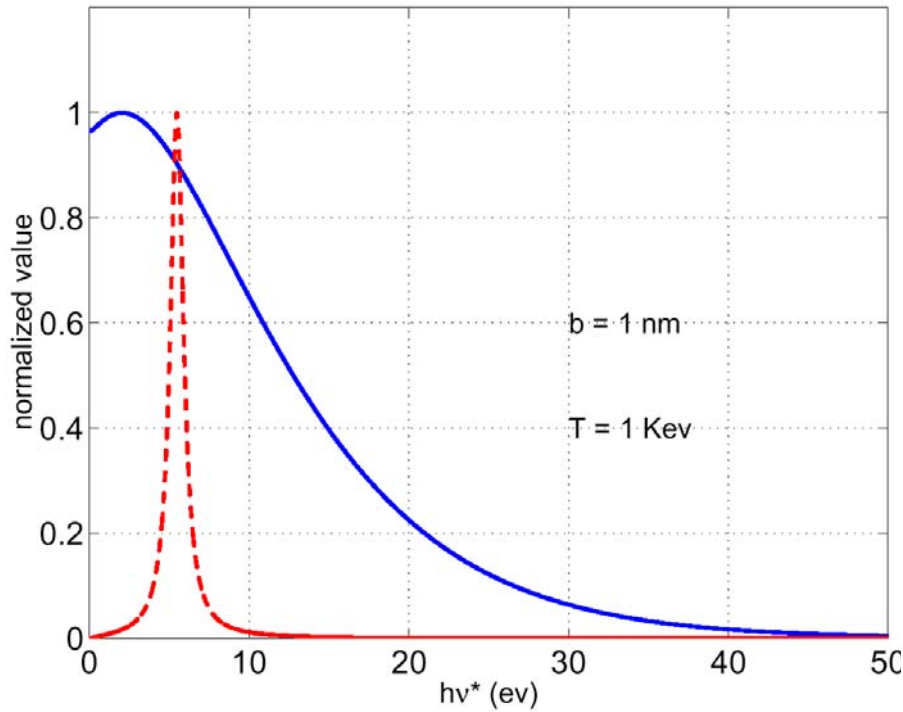


*"Energy Transfer Between Electrons and Photoresist: Its Relation to Resolution",*  
Geng Han and Franco Cerrina, J. Vac. Sci. Technol. B18 p3297 (2000)





# Energy Transfer



Electrons become bluer and dimmer as their energy increases



*"Energy Transfer Between Electrons and Photoresist: Its Relation to Resolution",*  
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# EELS Spectrum (SiN)

